


Issue Classification 	Application/Control No. 10764200	Applicant(s)/Patent Under Reexamination LEE ET AL.
	Examiner Wiehe, Nathan	Art Unit 3745

[illegible]

Wiehe, Nathan <i>Nathan Wiehe</i> (Assistant Examiner) (Date) 1/8/08	<i>Edward K Look</i> EDWARD K LOOK	Total Claims Allowed: 15	
(Legal Instruments Examiner) (Date)	SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) (Date) <i>1/18/08</i>	O.G. Print Claim(s) 1	O.G. Print Figure 1